

Notice of Allowability

Application No.

10/803,855

Examiner

Emmanuel Hailemariam

Applicant(s)

CHANG ET AL.

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-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address--

All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTOL-85) or other appropriate communication will be mailed in due course. **THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS.** This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308.

1. ☒ This communication is responsive to 07/09/2007.
2. ☒ The allowed claim(s) is/are 1-12.
3. ☒ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
 - a) ☒ All b) ☐ Some* c) ☐ None of the:
 1. ☒ Certified copies of the priority documents have been received.
 2. ☐ Certified copies of the priority documents have been received in Application No. _____.
 3. ☐ Copies of the certified copies of the priority documents have been received in this national stage application from the International Bureau (PCT Rule 17.2(a)).

* Certified copies not received: _____.

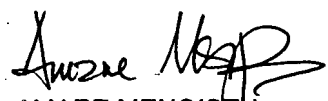
Applicant has THREE MONTHS FROM THE "MAILING DATE" of this communication to file a reply complying with the requirements noted below. Failure to timely comply will result in ABANDONMENT of this application.

THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.

4. ☐ A SUBSTITUTE OATH OR DECLARATION must be submitted. Note the attached EXAMINER'S AMENDMENT or NOTICE OF INFORMAL PATENT APPLICATION (PTO-152) which gives reason(s) why the oath or declaration is deficient.
 5. ☐ CORRECTED DRAWINGS (as "replacement sheets") must be submitted.
 - (a) ☐ including changes required by the Notice of Draftsperson's Patent Drawing Review (PTO-948) attached
 - 1) ☐ hereto or 2) ☐ to Paper No./Mail Date _____.
 - (b) ☐ including changes required by the attached Examiner's Amendment / Comment or in the Office action of Paper No./Mail Date _____.
- Identifying indicia such as the application number (see 37 CFR 1.84(c)) should be written on the drawings in the front (not the back) of each sheet. Replacement sheet(s) should be labeled as such in the header according to 37 CFR 1.121(d).
6. ☐ DEPOSIT OF and/or INFORMATION about the deposit of BIOLOGICAL MATERIAL must be submitted. Note the attached Examiner's comment regarding REQUIREMENT FOR THE DEPOSIT OF BIOLOGICAL MATERIAL.

Attachment(s)

1. ☐ Notice of References Cited (PTO-892)
2. ☐ Notice of Draftsperson's Patent Drawing Review (PTO-948)
3. ☐ Information Disclosure Statements (PTO/SB/08), Paper No./Mail Date _____
4. ☐ Examiner's Comment Regarding Requirement for Deposit of Biological Material
5. ☐ Notice of Informal Patent Application
6. ☐ Interview Summary (PTO-413), Paper No./Mail Date _____
7. ☐ Examiner's Amendment/Comment
8. ☒ Examiner's Statement of Reasons for Allowance
9. ☐ Other _____


AMARE MENGISTU
SUPERVISORY PATENT EXAMINER

REASONS FOR ALLOWANCE

1. Claims 1-12 are allowed over the prior art of record.

The following is an examiner's statement of reasons for allowance:

The prior art does not disclose or suggest the following Claim 1 limitations: "... applied in a thin film positioning device for detecting a coordinate value of a contact point under an environment of periodic noises, comprising the steps of: obtaining a first sampling value of the contact point at a first time point; obtaining a second sampling value of the contact point at a second time point, wherein the interval between the first time point and the second time point is roughly a half of the period of the periodic noise; determining if the absolute value of the difference between the first sampling value and the second sampling value is smaller than a first threshold value or not: if not, neglect this contact point and end the process of this method; obtain a third sampling value of the contact point at a third time point, wherein the interval between the third time point and the first time point is roughly a multiple of the period of the periodic noise; determining if the absolute value of the difference between the first sampling value and the third sampling value is smaller than a second threshold value or not: if not, neglect this contact point and end the process of this method; use the average value of the first sampling value and the second sampling value to obtain the coordinate of the contact point"; and claims 3 and 7 limitations "...a thin film X which has a first X-end and a second X-end a thin film Y which has a first Y-end and a second Y-end; a first switch Y coupled to the first Y-end and a ground end; a second switch

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Y coupled to the second Y-end and a power source; a first switch X coupled to the first X-end and the ground end; a second switch X coupled to the second X-end and the power source; of which, if a sampling point is to be sampled by the positioning device, the sampling point is the first X-end, the second X-end, the first Y-end or the second Y-end; first of all, a first sampling value of the sampling point is obtained at a first time point while a second sampling value of the sampling point is obtained at a second time point, wherein the interval between the first time point and the second time point is roughly a half of the period of the periodic noise; secondly, determine if the absolute value of the difference between the first sampling value and the second sampling value is smaller than a first threshold value or not: if not, neglect the contact point; obtain a third sampling value of the sampling point at a third time point, wherein the interval between the third time point and the first time point is roughly a multiple of the period of the periodic noise; next, determining if the absolute value of the difference between the first sampling value and the third sampling value is smaller than a second threshold value or not: if not, neglect the contact point; lastly, the positioning device uses the average value of the first sampling value and the second sampling value to obtain the coordinate value of the contact point; in combination with the remaining claim elements as set forth in Claims 1, 3 and 7 and their depending claims 2, 4-6 and 8-12. *Therefore* claims 1-12 are allowed.

2. Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays,

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should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

3. Any inquiry concerning this communication or earlier communications from the examiner should be directed to **Emmanuel Hailemariam** whose telephone number is **(571) 270-1545**. The examiner can normally be reached on MTWTHF from 8 to 5. If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Amare Mengistu, can be reached on **(571) 272-7674**. Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the Group receptionist whose telephone number is (571)-273-8300.
4. Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Examiner: Emmanuel Hailemariam

August 4, 2007


AMARE MENGISTU
SUPERVISORY PATENT EXAMINER